

FCC ID: 2ASV5-BRAVE6

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

WIFI:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
802.11b	2.412	9.7	9.33	8.7±1	9.7	9.33	<5	2.89880	3.00	YES
	2.442	9.3	8.51	8.7±1	9.7	9.33	<5	2.91677	3.00	YES
	2.462	9.5	8.91	8.7±1	9.7	9.33	<5	2.92869	3.00	YES
802.11g	2.412	3.4	2.19	4±1	5	3.16	<5	0.98224	3.00	YES
	2.442	3.9	2.45	4±1	5	3.16	<5	0.98833	3.00	YES
	2.462	4.1	2.57	4±1	5	3.16	<5	0.99237	3.00	YES
802.11n HT20	2.412	3.4	2.19	4±1	5	3.16	<5	0.98224	3.00	YES
	2.442	3.9	2.45	4±1	5	3.16	<5	0.98833	3.00	YES
	2.462	4.1	2.57	4±1	5	3.16	<5	0.99237	3.00	YES
802.11n HT40	2.412	2.8	1.91	3±1	4	2.51	<5	0.78022	3.00	YES
	2.442	3.1	2.04	3±1	4	2.51	<5	0.78506	3.00	YES
	2.452	3.3	2.14	3±1	4	2.51	<5	0.78667	3.00	YES

Conclusion:

For the max result : $2.92869 \leq 3.0$ for Max Power Density, compliance RF exposure.

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Signature:

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